

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/628,900	ZARRIEFF ET AL.	
Examiner	Art Unit	
James K. Trujillo	2116	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB), see attached; NPL: IEEE; Inventor Search/DP; see attached	3/22/2006	JKT		